

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>		Docket Number (Optional) UC01-161-2	Application Number 10/039,290
		Applicant(s) ALI SHAKOURI ET AL.	
Filing Date JANUARY 4, 2002		Group Art Unit 8836 2627	

*EXAMINER INITIAL	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)
CS	Baliga, J. et al.; "SUBSURFACE MICROSCOPY OF BIASED METAL-OXIDE-SEMICONDUCTOR FIELD EFFECT TRANSISTOR STRUCTURES: PHOTOTHERMAL AND ELECTROREFLECTANCE IMAGES," Sensors and Actuators, A71, pp. 40 thru 45, (1998).
CS	Claeys, W. et al.; "THERMOREFLECTANCE OPTICAL TEST PROBE FOR THE MEASUREMENT OF CURRENT INDUCED TEMPERATURE CHANGES IN MICROELECTRIC COMPONENTS," Quality and Reliability Engineering International, Vol. 9, pp. 303-308, (1993).
CS	Csendes, A. et al.; "THERMAL MAPPING WITH LIQUID CRYSTAL METHOD," Microelectronic Engineering, Vol. 31, pp. 281-290, (1996).
CS	Cutolo, Antonello; "SELECTED CONTACTLESS OPTOELECTRONIC MEASUREMENTS FOR ELECTRONIC APPLICATIONS (Invited)," Review of Scientific Instruments, Vol. 69, No. 2; pp. 337-360, February, 1998.
CS	Garfinkel, J. et al.; "PIEZOREFLECTIVITY OF THE NOBLE METALS," Physical Review, Vol. 115, No. 1; pp. 695-706, August, 1966.
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CS	Kolzer, J. et al.; "THERMAL IMAGING AND MEASUREMENT OF TECHNIQUES FOR ELECTRONIC MATERIALS AND DEVICES," Microelectronic Engineering, Vol. 31, pp. 251-270, (1996).
CS	Kondo, Seiichi et al.; "HIGH RESOLUTION TEMPERATURE MEASUREMENT OF VOID DYNAMICS INDUCED BY ELECTROMIGRATION IN ALUMINUM METALLIZATION," Applied Physics Letters, Vol. 67, No. 11, pp. 1606-1608, September, 1995.
CS	Langer, G. et al.; "THERMAL CONDUCTIVITY OF THIN METALLIC FILMS MEASURED BY PHOTOTHERMAL PROFILE ANALYSIS," Review of Scientific Instruments, Vol. 68, No. 3, pp. 1510-1513, March, 1997.
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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Lee, A. S. and Norris, P.M.; "A NEW OPTICAL METHOD FOR MEASURING SURFACE TEMPERATURE AT LARGE INCIDENT PROBE ANGLES," Review of Scientific Instruments, Vol. 68, No. 2, pp. 1307-1311, February, 1997.

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Vertikov, M. et al.; "TIME RESOLVED PUMP-PROBE EXPERIMENTS WITH SUBWAVELENGTH LATERAL RESOLUTION," Applied Physics Letters, Vol. 69, No. 21, pp. 2465-2467, October, 1996.

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Elad, Michael and Feuer, Arie; "RESTORATION OF A SINGLE SUPERRESOLUTION IMAGE FROM SEVERAL BLURRED, NOISY, AND UNDERSAMPLED MEASURED IMAGES," IEEE Transactions on Image Processing, Vol. 6, No. 12, pp. 1646-1658, December, 1997.

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